

Yoshitaka Naitoh

List of Publications by Year in descending order

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55
papers

1,227
citations

430874

18
h-index

377865

34
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56
all docs

56
docs citations

56
times ranked

1375
citing authors

#	ARTICLE	IF	CITATIONS
1	Study of high-resolution KPFM on a pn-patterned Si surface. <i>Microscopy</i> (Oxford, England), 2022, 71, 98-103.	1.5	5
2	Local spectroscopic imaging of a single quantum dot in photoinduced force microscopy. <i>Applied Physics Letters</i> , 2022, 120, .	3.3	6
3	Nanoscale optical imaging with photoinduced force microscopy in heterodyne amplitude modulation and heterodyne frequency modulation modes. <i>Journal of Photochemistry and Photobiology C: Photochemistry Reviews</i> , 2022, 52, 100532.	11.6	5
4	Optical force mapping at the single-nanometre scale. <i>Nature Communications</i> , 2021, 12, 3865.	12.8	30
5	Atomic-Scale Elastic Property Probed by Atomic Force Microscopy. , 2019, , 33-52.		0
6	Kelvin Probe Force Microscopy with. <i>Springer Series in Surface Sciences</i> , 2018, , 437-463.	0.3	1
7	Stable contrast mode on TiO ₂ (110) surface with metal-coated tips using AFM. <i>Ultramicroscopy</i> , 2018, 191, 51-55.	1.9	13
8	Direct Visualization of Oxygen Reaction with Paired Hydroxyl on TiO ₂ (110) Surface at 78 K by Atomic Force Microscopy. <i>Journal of Physical Chemistry C</i> , 2018, 122, 17395-17399.	3.1	6
9	Charge State and Charge Manipulation of Oxygen Molecules Adsorbed on Rutile TiO ₂ (110) Surface by Kelvin Probe Force Microscopy. <i>Vacuum and Surface Science</i> , 2018, 61, 639-644.	0.1	0
10	Investigation of tunneling current and local contact potential difference on the TiO ₂ (110) surface by AFM/KPFM at 78 K. <i>Nanotechnology</i> , 2017, 28, 105704.	2.6	20
11	Subatomic-scale force vector mapping above a Ge(001) dimer using bimodal atomic force microscopy. <i>Nature Physics</i> , 2017, 13, 663-667.	16.7	19
12	Separation of atomic-scale spin contrast on NiO(001) by magnetic resonance force microscopy. <i>Journal of Physics Condensed Matter</i> , 2017, 29, 404001.	1.8	0
13	Development of low temperature atomic force microscopy with an optical beam deflection system capable of simultaneously detecting the lateral and vertical forces. <i>Review of Scientific Instruments</i> , 2016, 87, 093113.	1.3	20
14	Growth models of coexisting <i>p</i> (2 Å ⁻¹) and <i>c</i> (6 Å ⁻²) phases on an oxygen-terminated Cu(110) surface studied by noncontact atomic force microscopy at 78 K. <i>Nanotechnology</i> , 2016, 27, 205702.	2.6	2
15	Distance dependence of atomic-resolution near-field imaging on γ -Al ₂ O ₃ (0001) surface with respect to surface photovoltage of silicon probe tip. <i>Nano Research</i> , 2016, 9, 530-536.	10.4	1
16	Development of the Magnetic Exchange Force Microscopy Using Ferromagnetic Resonance to Image Surface Spin with Atomic Resolution. <i>Hyomen Kagaku</i> , 2016, 37, 416-421.	0.0	0
17	Atomic-Resolution Imaging of the Optical Near Field Based on the Surface Photovoltage of a Silicon Probe Tip. <i>Physical Review Applied</i> , 2015, 3, .	3.8	6
18	Atomic force microscopy identification of Al-sites on ultrathin aluminum oxide film on NiAl(110). <i>Nanotechnology</i> , 2015, 26, 505704.	2.6	8

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19	Surface potential imaging with atomic resolution by frequency-modulation Kelvin probe force microscopy without bias voltage feedback. <i>Nanotechnology</i> , 2015, 26, 195701.	2.6	21
20	Magnetic force microscopy using tip magnetization modulated by ferromagnetic resonance. <i>Nanotechnology</i> , 2015, 26, 125701.	2.6	17
21	Spin-selective Imaging by Magnetic Exchange Force Microscopy Using Ferromagnetic Resonance. <i>Microscopy (Oxford, England)</i> , 2014, 63, i11.2-i11.	1.5	0
22	The stray capacitance effect in Kelvin probe force microscopy using FM, AM and heterodyne AM modes. <i>Nanotechnology</i> , 2013, 24, 225701.	2.6	45
23	Force Mapping of the NaCl(100)/Cu(111) Surface by Atomic Force Microscopy at 78 K. <i>Japanese Journal of Applied Physics</i> , 2012, 51, 035201.	1.5	1
24	High potential sensitivity in heterodyne amplitude-modulation Kelvin probe force microscopy. <i>Applied Physics Letters</i> , 2012, 100, .	3.3	51
25	Quantification of Atomic Scale Elasticity on Ge(001). $\langle \text{mml:mi} \rangle \langle \text{mml:mi} \rangle \langle \text{mml:mo} \text{stretchy="false"} \rangle \langle \text{mml:mn} \rangle 4 \langle \text{mml:mn} \rangle \langle \text{mml:mo} \rangle \text{Tj ETQq1 1 0.784314 rgBT /Overlock 10 Tf 50 502 Td (mathvariant="bo}$	7.8	4
26	Tungsten-Coated Tip. <i>Physical Review Letters</i> , 2012, 109, 215501. Complex design of dissipation signals in non-contact atomic force microscopy. <i>Physical Chemistry Chemical Physics</i> , 2012, 14, 16250.	2.8	11
27	Fabrication of sharp tungsten-coated tip for atomic force microscopy by ion-beam sputter deposition. <i>Review of Scientific Instruments</i> , 2011, 82, 113707.	1.3	21
28	Switching surface polarization of atomic force microscopy probe utilizing photoisomerization of photochromic molecules. <i>Journal of Applied Physics</i> , 2011, 109, 064308.	2.5	4
29	Multifrequency high-speed phase-modulation atomic force microscopy in liquids. <i>Ultramicroscopy</i> , 2010, 110, 582-585.	1.9	25
30	Step response measurement of AFM cantilever for analysis of frequency-resolved viscoelasticity. <i>Ultramicroscopy</i> , 2010, 110, 612-617.	1.9	10
31	High force sensitivity in Q-controlled phase-modulation atomic force microscopy. <i>Applied Physics Letters</i> , 2010, 97, .	3.3	8
32	Simultaneous observation of surface topography and elasticity at atomic scale by multifrequency frequency modulation atomic force microscopy. <i>Journal of Vacuum Science and Technology B: Nanotechnology and Microelectronics</i> , 2010, 28, 1210-1214.	1.2	25
33	Effect of Surface Stress around the S_{A} Step of Si(001) on the Dimer Structure Determined by Noncontact Atomic Force Microscopy at 5 K. <i>Journal of the Physical Society of Japan</i> , 2010, 79, 013601.	1.6	14
34	Development of atomic force microscope with wide-band magnetic excitation for study of soft matter dynamics. <i>Review of Scientific Instruments</i> , 2009, 80, 023705.	1.3	17
35	The influence of a Si cantilever tip with/without tungsten coating on noncontact atomic force microscopy imaging of a Ge(001) surface. <i>Nanotechnology</i> , 2009, 20, 264011.	2.6	24
36	Study of oxidized Cu(110) surface using noncontact atomic force microscopy. <i>Surface Science</i> , 2008, 602, 2175-2182.	1.9	18

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37	Atomic-Scale Imaging of B/Si(111) $\sqrt{3}\sqrt{3}$ Surface by Noncontact Atomic Force Microscopy. Japanese Journal of Applied Physics, 2008, 47, 8218.	1.5	2
38	Phase modulation atomic force microscopy in constant excitation mode capable of simultaneous imaging of topography and energy dissipation. Applied Physics Letters, 2008, 92, 121903.	3.3	11
39	High-Speed Phase-Modulation Atomic Force Microscopy in Constant-Amplitude Mode Capable of Simultaneous Measurement of Topography and Energy Dissipation. Japanese Journal of Applied Physics, 2008, 47, 6121.	1.5	13
40	Scanning Tunneling Microscopy and Spectroscopy Studies of Individual Lander Molecules Anchored on a Copper Oxide Nanotemplate. Journal of Physical Chemistry C, 2008, 112, 16118-16122.	3.1	12
41	Theoretical investigation on force sensitivity in Q-controlled phase-modulation atomic force microscopy in constant-amplitude mode. Journal of Applied Physics, 2008, 103, 054305.	2.5	6
42	Dissipative force modulation Kelvin probe force microscopy applying doubled frequency ac bias voltage. Applied Physics Letters, 2007, 90, 033118.	3.3	7
43	Elimination of instabilities in phase shift curves in phase-modulation atomic force microscopy in constant-amplitude mode. Applied Physics Letters, 2007, 90, 194104.	3.3	28
44	Force Microscopy Imaging of Rest Atom on Si(111) $\sqrt{7}\sqrt{7}$ Surface under Strong Tip-Surface Interaction. Journal of the Physical Society of Japan, 2007, 76, 033601.	1.6	2
45	Influence of Surface Stress on the Phase Change in a Si(001) Step Measured by LT-NC-AFM. Hyomen Kagaku, 2007, 28, 421-427.	0.0	0
46	High-Sensitivity Force Detection by Phase-Modulation Atomic Force Microscopy. Japanese Journal of Applied Physics, 2006, 45, L793-L795.	1.5	21
47	Origin of $p(2\sqrt{3}\times\sqrt{3})$ Phase on Si(001) by Noncontact Atomic Force Microscopy at 5 ÅK. Physical Review Letters, 2006, 96, 106104.	7.8	52
48	Wideband and hysteresis-free regulation of piezoelectric actuator based on induced current for high-speed scanning probe microscopy. Review of Scientific Instruments, 2006, 77, 103701.	1.3	10
49	Electronic structures of Ag/Ge(001) surfaces. Surface Science, 2005, 591, 108-116.	1.9	4
50	One-Dimensional Assembly and Selective Orientation of Lander Molecules on an O^{H} -Cu Template. Angewandte Chemie - International Edition, 2004, 43, 2092-2095.	13.8	99
51	Nanostructuring Cu Surfaces Using Custom-Designed Molecular Molds. Nano Letters, 2004, 4, 75-78.	9.1	42
52	Properties of large organic molecules on metal surfaces. Progress in Surface Science, 2003, 71, 95-146.	8.3	419
53	Formation process of very thin Ag structures on Ge(001) surface below RT. Surface Science, 2002, 513, 1-8.	1.9	6
54	Simultaneous observation of scanning tunneling microscopy and reflection electron microscopy image of the Si(111) $\sqrt{7}\sqrt{7}$ surface. Surface Science, 1999, 433-435, 627-631.	1.9	7

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55	SURFACE TRANSMISSION ELECTRON MICROSCOPY ON STRUCTURES WITH TRUNCATION. <i>Surface Review and Letters</i> , 1997, 04, 687-694.	1.1	2